metal-organic papers

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Key indicators

Single-crystal X-ray study T = 293 KMean $\sigma(C-C) = 0.004 \text{ Å}$ R factor = 0.032 wR factor = 0.081 Data-to-parameter ratio = 23.7

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e. Bis(*N*-cyclohexyl-*N*-methyldithiocarbamato)dimethyltin(IV)

The molecule of the title compound, $[Sn(CH_3)_2(C_8H_{14}NS_2)_2]$, occupies a special position on a crystallographic mirror plane which coincides with the plane of the dimethyltin group. The severely distorted coordination tetrahedron formed by the four strong bonds of the Sn atom $[Sn-C = 2.101 (4) \text{ and } 2.108 (5) \text{ Å}, Sn-S = 2.5169 (7) \text{ Å}, C-Sn-C = 137.0 (2)^{\circ}$ and $S-Sn-S = 84.46 (3)^{\circ}]$ is expanded to a distorted octahedron due to weak intramolecular $Sn \cdots S$ interactions of 2.9785 (6) Å.

Comment

The comparison of the geometry of numerous bis(dithiocarbamato)dimethyltin and bis(dithiocarbamato)diphenyltin complexes reveals interesting differences. It turns out that dimethyltin complexes show, in most cases, substantially larger C-Sn-C angles than their diphenyltin analogues [*e.g.* 136.0 (1)° in Me₂Sn(S₂CNMe₂)₂ (Kimura *et al.*, 1972) and 101.4 (6)° in Ph₂Sn(S₂CNEt₂)₂ (Lindley & Carr, 1974)]. Furthermore, in diphenyltin complexes, one of the ligands usually chelates the Sn atom symmetrically, whereas the other ligand shows a considerable difference in the Sn-S bond distances. By contrast, in dimethyltin complexes, both ligands display the same coordination pattern, with one shorter Sn-S bond and one longer Sn···S 'secondary' contact.



The geometry of the title compound, (I), is typical for the bis(dithiocarbamato)dimethyltin complexes and illustrates the features outlined above. Just as in its analogue, bis[*N*,*N*-bis(2-hydroxyethyl)dithiocarbamato]dimethyltin(IV) (Farina *et al.*, 2000), molecule (I) has a crystallographic mirror plane, coinciding with the C9/Sn1/C10 plane. The severely distorted coordination tetrahedron formed by the four strong bonds of the Sn atom [Sn1-C9 = 2.101 (4), Sn1-C10 = 2.108 (5) and Sn1-S1 = 2.5169 (7) Å; C9-Sn1-C10 = 137.0 (2)° and S1-Sn1-S1ⁱ = 84.46 (3)°; symmetry code: (i) $x, \frac{3}{2} - y, z$] is expanded to a distorted octahedron due to weak intramolecular Sn1...S2 interactions of 2.9785 (6) Å, the S2-Sn1-S2ⁱ angle being 146.35 (2)°.

The Sn atom shows a very small displacement from the plane of the coordinating atoms S1, S2, S1A and S2A [0.0048 (8) Å]; the four-membered chelate ring is almost planar and the torsion angle Sn1-S1-C8-S2 is -6.89 (15)°.

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Experimental

To a solution of *N*-methylcyclohexylamine (3.9 ml, 0.04 mol) in ethanol was added, with stirring at 273 K, carbon disulfide (1.8 ml, 0.03 mol). After stirring for 2 h, 3.295 g (0.015 mol) of dimethyl-tin(IV) chloride (10.00 ml) was added dropwise to the mixture. The mixture was then stirred vigorously for 1 h. The resulting white solid was recrystallized from chloroform.

Mo $K\alpha$ radiation

reflections $\theta = 2.0-27.6^{\circ}$

 $\mu = 1.44 \text{ mm}^{-1}$

T = 293 (2) K

Block, light yellow

 $0.27 \times 0.22 \times 0.16 \text{ mm}$

Cell parameters from 4467

Crystal data

Data collection

Bruker SMART APEX CCD area- detector diffractometer ω scans Absorption correction: multi-scan	2795 independent reflections 2441 reflections with $I > 2\sigma(I)$ $R_{\text{int}} = 0.029$ $\theta_{\text{max}} = 27.6^{\circ}$
(SADABS; Sheldrick, 1996)	$h = -17 \rightarrow 16$
$T_{\rm min} = 0.696, T_{\rm max} = 0.802$	$k = -25 \rightarrow 25$
15359 measured reflections	$l = -11 \rightarrow 11$

Refinement

Refinement on F^2	$w = 1/[\sigma^2(F_o^2) + (0.0415P)^2]$
$R[F^2 > 2\sigma(F^2)] = 0.032$	+ 0.8626P]
$wR(F^2) = 0.081$	where $P = (F_o^2 + 2F_c^2)/3$
S = 1.06	$(\Delta/\sigma)_{\rm max} < 0.001$
2795 reflections	$\Delta \rho_{\rm max} = 0.74 \ {\rm e} \ {\rm \AA}^{-3}$
118 parameters	$\Delta \rho_{\rm min} = -0.33 \text{ e} \text{ Å}^{-3}$
H-atom parameters constrained	

Table 1

Selected geometric parameters (Å, °).

Sn1-S1	2.5169 (7)	S2-C8	1.693 (3)
Sn1-S2	2.9785 (6)	C6-N1	1.482 (3)
Sn1-C9	2.101 (4)	C7-N1	1.457 (3)
Sn1-C10	2.108 (5)	C8-N1	1.330 (3)
S1-C8	1.748 (2)		
S1-Sn1-S1 ⁱ	84.46 (3)	C10-Sn1-S1	107.28 (10)
S2-Sn1-S2 ⁱ	146.35 (2)	C8-S1-Sn1	95.09 (8)
C9-Sn1-C10	137.0 (2)	S2-C8-S1	118.81 (13)
C9-Sn1-S1	104.23 (13)		

Symmetry code: (i) $x, \frac{3}{2} - y, z$.



Figure 1

The molecular structure of the title compound, (I), with 50% probability displacement ellipsoids

After their location in a difference map, all H atoms were placed geometrically at ideal positions and allowed to ride on the parent atoms, with C-H = 0.93-0.97 Å. However, the H atoms at C9 and C10 were located in the map, refined initially, and then constrained.

Data collection: *SMART* (Siemens, 1996); cell refinement: *SAINT* (Siemens, 1996); data reduction: *SAINT*; program(s) used to solve structure: *SHELXTL* (Sheldrick, 1997); program(s) used to refine structure: *SHELXTL*; molecular graphics: *SHELXTL*; software used to prepare material for publication: *SHELXTL*, *PARST* (Nardelli, 1995) and *PLATON* (Spek, 1990).

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